

PTO-1449 REPRODUCED <div style="border: 1px solid black; border-radius: 50%; width: 100px; height: 100px; display: flex; align-items: center; justify-content: center; margin: 10px auto;"> <div style="writing-mode: vertical-rl; transform: rotate(180deg); font-size: 8px;">PATENT &amp; TRADEMARK OFFICE</div> <div style="text-align: center;"> <div style="font-size: 24px; font-weight: bold;">OIP</div> <div style="font-size: 12px;">FEB 03 2003</div> </div> </div> SUPPLEMENTAL INFORMATION DISCLOSURE CITATION IN AN APPLICATION January 29, 2003 (Use several sheets if necessary)		ATTORNEY DOCKET NO. 0717.2022-000		APPLICATION NO. 10/022,190				
APPLICANT Matthew Zavracky, et al.								
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U.S. PATENT DOCUMENTS								
EXAM- INER INI- TIAL		DOCUMENT NUMBER	ISSUE DATE / PUBLICATION DATE	NAME				
✓ RK	AC2	5,422,751	06/06/1995	Lewis, et al.				
✓ RK	AD2	5,508,834	04/16/1996	Yamada, et al.				
✓ RK	AE2	5,999,237	12/07/1999	Miyawaki, et al.				
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO	
✓ RK	AM	DE 3408176 A1	19-SEP-1985	Germany				X
✓ RK	AN	JP 03189618	19-AUG-1991	Japan (Abstract)				
✓ RK	AO	JP 05165015	29-JUN-1993	Japan (Abstract)				
✓ RK	AP	JP 06258637	16-SEP-1994	Japan				X
✓ RK	AQ	JP 07225375	22-AUG-1995	Japan (Abstract)				
✓ RK	AL2	WO 98/19435	07-MAY-1998	PCT				
✓ RK	AM2	WO 99/23636	14-MAY-1999	PCT				
✓ RK	AN2	JP 2000075289	14-MAR-2000	Japan (Abstract)				
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
	AS							
	AT							
EXAMINER			DATE CONSIDERED					
			10/20/05					